

**Search Notes**

Application/Control No.

10/722,178

Examiner

Hai L. Nguyen

Applicant(s)/Patent under  
Reexamination

MASON, JAMES STEPHEN

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner
331	16,17	4/18/2005	HLN
327	311,312	—	—
327	551-559	—	—
Update	Search	9/30/2005	HLN
Update	Search	1/10/2006	HLN
Update	Search	7/3/2006	HLN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search, see search history printout	1/12/2006	HLN